EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	391	338/195.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:55
S2	582	374/185.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:57
S3	122	204/192.21.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:58
S4	3297	29/592.1,610.1,612.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:59
S5	38	thermally with trim\$5 with resistor	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 10:06
S6	6	S1 and S5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:59
S7	0	S2 and S5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:59
S8	0	S3 and S5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:59
S9	2	S4 and S5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:59
S10	7	S6 or S9	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 09:59
S11	351	trim\$5 with resistor with heat\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 10:07
S12	563	temperature with (increas\$3 or rais\$3) with trim\$5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 10:08
S13	20	S11 and S12	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 10:08
S14	190195	temperature with constant	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 10:08
S15	7	S13 and S14	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 10:09

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S16	14	LANDSBERGER-LESLIE-M.in. or GRUDIN-OLEG.in. or FROLOV-GENNADIY.in.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:28
S17	351	trim\$5 with resistor with heat\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:30
S18	6	S17 and S16	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:28
S19	802	trim\$5 same resistor same heat\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:29
S20	6	S16 and S19	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:29
S21	129	(trim\$5 near resistor) with heat\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:46
S22	88	S21 and @ad<"20010910"	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:31
S23	190195	temperature with constant	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:31
S24	19	S23 and S22	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:31
S25	0	(trim\$5 near resistor) with (heat\$3 near pluse)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:46
S26	: 4	(trim\$5 near resistor) with (heat\$3 near pulse)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:48
S27	293	heat\$3 near resister	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:49
S28	3	trim\$4 with (heat\$3 near resister)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/10 14:49

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S29	28	("20010001493" "20020033519" "4041440" "4210996" "4472239" "4606781" "4683442" "4717886" "4782202" "4870472" "4902959" "5081439" "5110758" "5363084" "5460040" "5466484" "5493148" "5557252" "5563549" "5635893" "5679275" "5742307" "5757264" "5844122" "6097276" "6184494" "6255185" "6667683").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/10/11 07:12
S30	0	S29 and (micro-platform)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/11 07:13
S31	20	(micro-platform)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/11 07:13
S32	14	LANDSBERGER-LESLIE-M.in. or GRUDIN-OLEG.in. or FROLOV-GENNADIY.in.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/11 07:13
S33	5	S31 and S32	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/10/11 07:13



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IEE CNF	IEE Conference Proceeding	Feldbaumer, D.W.; Babcock, J.A.; Mercier, V.M.; Chun, C.K.Y.; Electron Devices, IEEE Transactions on
IEEE STD	IEEE Standard	Volume 42, Issue 4, April 1995 Page(s):689 - 696 Digital Object Identifier 10.1109/16.372073
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		2. Precision electrical trimming of very low TCR poly-SiGe resistors Babcock, J.A.; Francis, P.; Bashir, R.; Kabir, A.E.; Schroder, D.K.; Lee, M.S.L.; Yindeepol, W.; Prasad, S.J.; Kalnitsky, A.; Thomas, M.E.; Haggag, H.; Egan, K Jansen, P.; Electron Device Letters, IEEE Volume 21, Issue 6, June 2000 Page(s):283 - 285 Digital Object Identifier 10.1109/55.843151
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		3. Electrical trimming of ion-beam-sputtered polysilicon resistors by high conduction Das, S.; Lahiri, S.K.; Electron Devices, IEEE Transactions on Volume 41, Issue 8, Aug. 1994 Page(s):1429 - 1434 Digital Object Identifier 10.1109/16.297739
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		4. Investigation of conduction mechanism in thick film resistors trimmed by voltage method, Tobita, T.; Takasago, H.; Kariya, K.; Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [Trans. on Components, Packaging, and Manufacturing Technology, Part A, B, Volume 15, Issue 4, Aug. 1992 Page(s):583 - 589 Digital Object Identifier 10.1109/33.159889 AbstractPlus Full Text: PDF(612 KB) IEEE JNL Rights and Permissions

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US 20060063292 A1	20060323	Method for producing a packaged integrated circuit	438/51	438/50; 438/52	Landsberger; LeslieM
US 20060062272 A1	20060323	Measuring and trimming circuit components embedded in micro- platforms	374/43		Grudin; Oleg et al.
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US 20040101153 A1	20040527	Gas flow sensor, speaker system and microphone, utilizing measurement absolute of time-variations in absolute pressure	381/357	381/351; 381/354; 381/71.1	Grudin, Oleg et al.